

# **Update Notification**

Document # : FPCN21107ZP3 Issue Date: 24 May 2017

Title of Change:	Update to FPCN21107ZP - Assembly & Test site transfer of DPAK products currently manufactured in ON Semiconductor Malaysia facility (SBN) to ON Semiconductor Vietnam (OSV) facility.	
Proposed Changed Material First Ship Date:	1 November 2017 (OSV parts may be available for earlier conversions)	
Current Material Last Order Date:	1 November 2017 Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.	
Current Material Last Delivery Date:	31 December 2017 The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory.	
Product Category:	Active components – Discrete components	
Contact information	Contact your local ON Semiconductor Sales Office or <phuong.hoang@onsemi.com></phuong.hoang@onsemi.com>	
Samples	Contact your local ON Semiconductor Sales Office to place sample order.  Sample requests are to be submitted no later than 45 days after publication of this change notification.	
Sample Availability Date:	Samples Available On Request	
PPAP Availability Date:	PPAP Available On Request	
Additional Reliability Data	Contact your local ON Semiconductor Sales Office or <cheanching.sim@onsemi.com>.</cheanching.sim@onsemi.com>	
Type of Notification	This is an update to a Final Product/Process Change Notification (FPCN) sent to customers. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>	
Change Category	Type of Change	
Process – Assembly	Move of all or part of assembly to a different location/site/subcontractor.	
Process – Assembly	Change of product marking	
Test Flow	Move of all or part of electrical wafer test and/or final test to a different location/site/subcontractor	
Equipment	Production from a new equipment/tool which uses the same basic technology (replacement equipment or extension of existing equipment pool) without change of process.	

### **Description and Purpose:**

This Update Notification (UN) is issued to communicate the transfer of Assembly and Test of DPAK products from ON Semiconductor Malaysia (SBN) to ON Semiconductor Vietnam (OSV) in order to ensure support for joint growth and alleviate SBN manufacturing capacity constraints.

The OSV produced devices will utilize the same BOM, Equipment, and Processes. No change to the SBN affected device list of the original FPCN. No change to the request for qualification of the Assembly & Test processes at the ON Semiconductor Vietnam facility announced in FPCN21107ZP, utilizing the OSV specific part numbers. Changing only Assy/Test location and device marking to facilitate site tracking and control.

The OSV part numbers, identified in FPCN21107ZP, are available to early adaptors for immediate SBN demand conversion. You can view a list of those OSV part numbers, cross referenced to the affected SBN part numbers listed in this Update notification, in the attached Excel file.

Upon completion of this transfer, DPAK demand will be sourced solely from OSV and will no longer be available from SBN. At that time, either the transferring SBN or the current OSV part numbers can be utilized to order these products from OSV.

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Reason / Motivation for Change:	Change benefits for customer(s):  Unconstrained Automotive Sourcing; Mfg floor space for future expansion  Sustained TS16949 Certification with the Same BOM / Equipment / Processes  Allow for increased support for Seremban packages that are currently constrained  OSV has been audited to VDA6.3  Risks for delayed conversion:  No Seremban supply after Dec 31, 2017  Limited ability to support bridge build availability.	
Anticipated impact on fit, form, function, reliability, product safety or manufacturability	No anticipated impacts.  The device(s) has been qualified and validated based on the same Product Specification. The device(s) has successfully passed the AEC-Q101 qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded.	
Sites Affected:  All site(s) not applicable ON Semiconductor site(s): External Foundry/Subcon site(s)  ON Seremban, Malaysia ON Dong Nai Province, Vietnam		
Marking of Parts/ Traceability of Change:		
Reliability Data Summary:  No Changes. Successfully Passed AEC-Q101 Qualification. Please refer to original FPCN		
Electrical Characteristic Summary:  No Changes. Electrical characteristics are not impacted. Please refer to original FPCN		

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## **List of affected Standard Parts:**

Transferring Malaysia (SBN) Part Number	Qualification Vehicle
NJVMJD122T4G	MJD340T4G
NJVMJD32CT4G	MJD340T4G
NJVMJD44H11RLG	MJD340T4G
NJVMJD45H11RLG	MJD340T4G
NJVMJD45H11T4G	MJD340T4G
NJVMJD253T4G	MJD340T4G
NJVMJD31CT4G	MJD340T4G
NVD6415ANLT4G	NTD6414ANT4G
NVD6416ANLT4G	NTD6414ANT4G
STD5406NT4G	NTD6414ANT4G
SSRD8620CTT4G	MURHD560T4G
SSRD8620CTT4RG	MURHD560T4G
SURD8320T4G	MURHD560T4G
NTDV20P06LT4G	MTD6N20ET4G
STD18N06LT4G	MTD6N20ET4G
STD3055L104T4G	MTD6N20ET4G
NTDV3055L104T4G	MTD6N20ET4G
NVD2955T4G	MTD6N20ET4G
NRVBD640CTT4G	MBRD5H100T4G
SBR660CTT4G	MBRD5H100T4G
SBR640CTT4G	MBRD5H100T4G
SBRD81035CTLT4G	MBRD5H100T4G
SBRD8360T4G	MBRD5H100T4G

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